

# Pavel Vegeles

## List of Publications by Year in Descending Order

**Source:** <https://exaly.com/author-pdf/6720126/pavel-vegeles-publications-by-year.pdf>

**Version:** 2024-04-27

This document has been generated based on the publications and citations recorded by exaly.com. For the latest version of this publication list, visit the link given above.

The third column is the impact factor (IF) of the journal, and the fourth column is the number of citations of the article.

48  
papers

359  
citations

11  
h-index

16  
g-index

48  
ext. papers

397  
ext. citations

1.7  
avg, IF

3.13  
L-index

#	Paper	IF	Citations
48	Communication Electron-Beam Stimulated Release of Dislocations from Pinning Sites in GaN. <i>ECS Journal of Solid State Science and Technology</i> , <b>2022</b> , 11, 015003	2	
47	GaAs diodes for TiT-based betavoltaic cells. <i>Applied Radiation and Isotopes</i> , <b>2022</b> , 179, 110030	1.7	3
46	Investigation of the Effect of Irradiation by a Low-Energy Electron Beam on the Capacitance-Voltage Characteristics of SiO <sub>2</sub> . <i>Journal of Surface Investigation</i> , <b>2021</b> , 15, 1045-1048	0.5	
45	Parasitic p-n junctions formed at V-pit defects in p-GaN. <i>Journal of Applied Physics</i> , <b>2021</b> , 129, 155702	2.5	1
44	Experimental estimation of electron-hole pair creation energy in Ga <sub>2</sub> O <sub>3</sub> . <i>Applied Physics Letters</i> , <b>2021</b> , 118, 202106	3.4	8
43	Estimations of Activation Energy for Dislocation Mobility in p-GaN. <i>ECS Journal of Solid State Science and Technology</i> , <b>2021</b> , 10, 026004	2	1
42	Photosensitivity of Ga <sub>2</sub> O <sub>3</sub> Schottky diodes: Effects of deep acceptor traps present before and after neutron irradiation. <i>APL Materials</i> , <b>2020</b> , 8, 111105	5.7	13
41	Charging Effects in Al-SiO <sub>2</sub> -p-Si Structures After Low-Energy Electron Beam Irradiation. <i>Journal of Electronic Materials</i> , <b>2020</b> , 49, 5178-5183	1.9	3
40	Role of hole trapping by deep acceptors in electron-beam-induced current measurements in Ga <sub>2</sub> O <sub>3</sub> vertical rectifiers. <i>Journal Physics D: Applied Physics</i> , <b>2020</b> , 53, 495108	3	11
39	Comparative Study of Optical and Electrical Properties of Grown-In and Freshly Introduced Dislocations in GaN by SEM Methods. <i>Journal of Electronic Materials</i> , <b>2020</b> , 49, 5173-5177	1.9	1
38	Estimations of Low Temperature Dislocation Mobility in GaN. <i>Physica Status Solidi (A) Applications and Materials Science</i> , <b>2019</b> , 216, 1900163	1.6	3
37	Study of Extended Electrically Active Defects in Heterostructures Based on (Ga,Mn)As/(In,Ga)As by Electron Beam-Induced Current and Deep-Level Transient Spectroscopy. <i>Journal of Surface Investigation</i> , <b>2019</b> , 13, 105-110	0.5	0
36	On the mechanism of cross-hatch pattern formation in heterostructures with a small lattice mismatch. <i>Applied Surface Science</i> , <b>2019</b> , 479, 930-941	6.7	2
35	Recombination and optical properties of dislocations gliding at room temperature in GaN under applied stress. <i>Journal of Alloys and Compounds</i> , <b>2019</b> , 776, 181-186	5.7	12
34	Temperature Dependence of Low-Energy Electron Beam Irradiation Effect on Optical Properties of MQW InGaN/GaN Structures. <i>Physica Status Solidi (B): Basic Research</i> , <b>2018</b> , 255, 1700646	1.3	2
33	Structural investigation of light-emitting Al <sub>0.3</sub> B <sub>0.5</sub> structures grown on Ge/Si(100) substrate. <i>Journal of Physics: Conference Series</i> , <b>2018</b> , 1124, 022037	0.3	1
32	Investigation of the Effect of Electron-Beam Irradiation on the Defect Structure of Laterally Overgrown GaN Films via the Induced-Current and Cathodoluminescence Methods. <i>Journal of Surface Investigation</i> , <b>2018</b> , 12, 994-999	0.5	

31	Structural and optical characteristics of GaAs films grown on Si/Ge substrates. <i>Journal of Physics: Conference Series</i> , <b>2018</b> , 993, 012014	0.3	1
30	Dislocation glide in GaN films grown by the lateral-overgrowth method induced by low-energy electron-beam irradiation. <i>Journal of Surface Investigation</i> , <b>2016</b> , 10, 959-961	0.5	2
29	Radiation enhanced basal plane dislocation glide in GaN. <i>Japanese Journal of Applied Physics</i> , <b>2016</b> , 55, 05FM03	1.4	9
28	Effect of low-energy electron irradiation on the optical properties of structures containing multiple InGaN/GaN quantum well. <i>Semiconductors</i> , <b>2015</b> , 49, 143-148	0.7	4
27	Movement of basal plane dislocations in GaN during electron beam irradiation. <i>Applied Physics Letters</i> , <b>2015</b> , 106, 132101	3.4	19
26	Inverse bias effect on the optical properties of light-emitting diodes with multiple InGaN/GaN quantum wells when irradiated by an electron beam in a scanning electron microscope. <i>Journal of Surface Investigation</i> , <b>2015</b> , 9, 944-947	0.5	1
25	Dislocation gliding and cross-hatch morphology formation in AIII-BV epitaxial heterostructures. <i>Applied Physics Letters</i> , <b>2014</b> , 105, 231608	3.4	3
24	Low energy electron beam irradiation effect on optical properties of nanopillar MQW InGaN/GaN structures <b>2014</b> ,		1
23	Microcathodoluminescence spectra evolution for planar and nanopillar multi-quantum-well GaN-based structures as a function of electron irradiation dose. <i>Journal of Vacuum Science and Technology B: Nanotechnology and Microelectronics</i> , <b>2014</b> , 32, 011207	1.3	7
22	Temperature dependence of the cathodoluminescence spectra of irradiated light-emitting-diode structures with multiple InGaN/GaN quantum wells. <i>Journal of Surface Investigation</i> , <b>2013</b> , 7, 844-847	0.5	1
21	Role of extended defects in the transformation of InGaN/GaN multiple quantum well structure optical properties under low energy electron beam irradiation. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , <b>2013</b> , 10, 464-467		4
20	Influence of electron-beam irradiation in SEM on the cathodoluminescence and electron-beam-induced current in InGaN/GaN light-emitting diodes with a buried active region. <i>Journal of Surface Investigation</i> , <b>2012</b> , 6, 890-893	0.5	3
19	EBIC investigation of InGaN/GaN multiple quantum well structures irradiated with low energy electrons. <i>Journal of Physics: Conference Series</i> , <b>2011</b> , 281, 012013	0.3	5
18	Study of the effect of irradiation with the SEM electron beam on cathodoluminescence and the induced current in InGaN/GaN structures with multiple quantum wells. <i>Journal of Surface Investigation</i> , <b>2011</b> , 5, 945-948	0.5	9
17	Effect of low energy electron irradiation on optical properties of InGaN/GaN light emitting structures. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , <b>2011</b> , 8, 1265-1268		9
16	Effect of low-energy electron irradiation on the cathodoluminescence of multiple quantum well (MQW) InGaN/GaN structures. <i>Solid State Communications</i> , <b>2011</b> , 151, 208-211	1.6	14
15	Investigations of electron beam induced conductivity in silicon oxide thin films. <i>Journal of Surface Investigation</i> , <b>2010</b> , 4, 754-757	0.5	4
14	EBIC investigations of defect distribution in ELOG GaN films. <i>Physica B: Condensed Matter</i> , <b>2009</b> , 404, 4916-4918	2.8	4

13	EBIC and CL studies of ELOG GaN films. <i>Superlattices and Microstructures</i> , <b>2009</b> , 45, 308-313	2.8	14
12	Electrical properties and deep traps spectra in undoped M-plane GaN films prepared by standard MOCVD and by selective lateral overgrowth. <i>Journal of Crystal Growth</i> , <b>2009</b> , 311, 2923-2925	1.6	5
11	Study of dislocation EBIC image width in GaN films and GaN based structures. <i>Journal of Surface Investigation</i> , <b>2009</b> , 3, 58-60	0.5	6
10	Effects of laterally overgrown n-GaN thickness on defect and deep level concentrations. <i>Journal of Vacuum Science &amp; Technology B</i> , <b>2008</b> , 26, 990		36
9	Donor nonuniformity in undoped and Si doped n-GaN prepared by epitaxial lateral overgrowth. <i>Applied Physics Letters</i> , <b>2008</b> , 92, 042118	3.4	37
8	EBIC investigations of GaN layers prepared by epitaxial lateral overgrowth. <i>Journal of Surface Investigation</i> , <b>2008</b> , 2, 688-691	0.5	7
7	Comparative study of quantum efficiency of blue LED with different nanostructural arrangement. <i>Physica Status Solidi C: Current Topics in Solid State Physics</i> , <b>2007</b> , 4, 2981-2985		4
6	Defects with bright contrast in the induced-current mode in GaN-based light-emitting structures. <i>Journal of Surface Investigation</i> , <b>2007</b> , 1, 394-397	0.5	4
5	EBIC study of resistive photosensitive elements based on HgCdTe. <i>Semiconductors</i> , <b>2007</b> , 41, 235-239	0.7	1
4	Simulation and measurements of EBIC images of photoconductive elements based on HgCdTe. <i>Semiconductors</i> , <b>2007</b> , 41, 407-410	0.7	2
3	EBIC characterization of light-emitting structures based on GaN. <i>Semiconductors</i> , <b>2007</b> , 41, 491-494	0.7	12
2	Neutron Radiation Effects in Epitaxially Laterally Overgrown GaN Films. <i>Journal of Electronic Materials</i> , <b>2007</b> , 36, 1320-1325	1.9	28
1	Spatial variations of doping and lifetime in epitaxial laterally overgrown GaN. <i>Applied Physics Letters</i> , <b>2007</b> , 90, 152114	3.4	42